

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
09/833,863	FUNAKI, TOMOYUKI	
Examiner	Art Unit	
Sara M. Hanne	2179	

SEARCHED				
Class	Subclass	Date	Examiner	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
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East class/subclass search updated: USPat, PGPUB, EPO, JPO, Derwent, IBM tdb	2/18/2006	SMH